

Search Notes

Application/Control No.

10/615,955

Examiner

John D. Lee

Applicant(s)/Patent under
Reexamination

ONO ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
250	396R,400, 396ML	4/27/2005	JDL
250	397-399	4/27/2005	JDL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Files	Removed	4/27/2005	JDL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO "WEST" Database searched; search strategy on separate sheet.	4/27/2005	JDL